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BASIC EMC PUBLICATION

PUBLICATION FONDAMENTALE EN CEM

**Electromagnetic compatibility (EMC) –
Part 4-34: Testing and measurement techniques – Voltage dips, short
interruptions and voltage variations immunity tests for equipment with mains
current more than 16 A per phase**

**Compatibilité électromagnétique (CEM) –
Partie 4-34: Techniques d'essai et de mesure – Essais d'immunité aux creux de
tension, coupures brèves et variations de tension pour matériel ayant un
courant d'alimentation de plus de 16 A par phase**

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INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE
CODE PRIX

CG

ICS 33.100.20

ISBN 2-8318-1049-2

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –**Part 4-34: Testing and measurement techniques –
Voltage dips, short interruptions and voltage variations immunity tests
for equipment with mains current more than 16 A per phase**

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International Standard IEC 61000-4-34 has been prepared by subcommittee 77A: Low frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

It forms Part 4-34 of IEC 61000. It has the status of a Basic EMC Publication in accordance with IEC Guide 107.

This consolidated version of IEC 61000-4-34 consists of the first edition (2005) [documents 77A/498/FDIS and 77A/515/RVD], its amendment 1 (2009) [documents 77A/670/CDV and 77A/688/RVC] and its corrigendum 1 of November 2009.

The technical content is therefore identical to the base edition and its amendment and has been prepared for user convenience.

It bears the edition number 1.1.

A vertical line in the margin shows where the base publication has been modified by amendment 1.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication and its amendments will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
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- replaced by a revised edition, or
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INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)

Definitions, terminology

Part 2: Environment

Description of the environment

Classification of the environment

Compatibility levels

Part 3: Limits

Emission limits

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques

Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines

Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: 61000-6-1).